

micro resist 
technology

The experts for photoresists



The Experts for Photoresists

Innovation

Quality

Service

Know-how

Production of

Positive Tone Photoresists

Negative Tone Photoresists

ORMOCER®s

NanoImprint Resists

IR Baker (Infrared Baker)

Our Service

Microlithographic
processing of your substrates

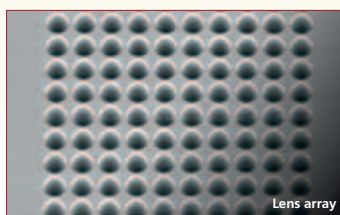
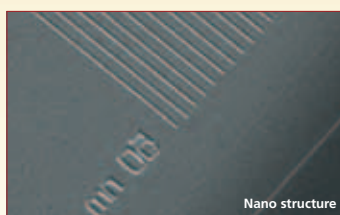
On-site support at
your facilities

Technical support

Flexible delivery quantities
free of extra charges

Short delivery times

Fast processing of
your orders



Applications

Micromotors

Microgears

Sensors

Actuators

Printing heads

MR/GMR heads

Ink jet elements

Hard drives

Contact bridges (BUMPS)

Microfluidics

Mikroreaction techniques

Memory chips

Processors and Controllers

RF elements

CD-/DVD-Mastering

Etch and moulding masks

Chips for beamers

Digital cameras

Beamsplitter

Switches and hubs

Scanners

Flexible Displays (OLED)

Communication devices

Nano stamps

Genetic engineering devices
and much more

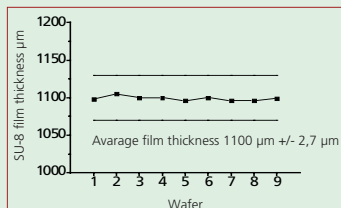
The Experts for Photoresists

Innovation

Quality

Service

Know-how



Highly reproducible film thickness in a series of SU-8 coated wafers



Preparation of a 1000 µm thick resist layer



UV imaging of a 300 µm thick SU-8 layer



UV imaging of a 30 µm thick micro coil



Electroformed Nickel coil - 30 µm



Mikrowave-plasma processor TEPLA 300 SEMI AUTO

Analytical services

- UV/Vis and NIR spectroscopy of solutions and films
- Scanning electron microscopy – characterisation with a magnification of up to 30.000

Photoresist modification

- ORMOCER®s with changed polymerisation initiator
- Customised ORMOCER® solutions (variation of film thickness)
- Customised resist solutions based on epoxy resins (SU-8), e.g. solvent variation
- Dyed photoresist solutions

Lithographic services

- Coating of different substrates (e.g. silicon, glass, ceramics, foils) with photoresists/polymers
 - Spin coating (5 inch)
 - Doctor's blading (15 cm x 30 cm)
- Preparation of ultra-thick resist films
 - Positive tone photoresists from 1 µm to 80 µm
 - Epoxies (SU-8) from 0.5 µm to 1500 µm
- Innovative bake processes by using of an Infrared baker (4 inch – 6 inch wafer)
- UV lithographic patterning (4 inch wafer)
 - SU-8 films up to 300 µm
 - Positive tone photoresist films up to 30 µm
 - Negative tone photoresist films up to 10 µm

O₂-plasma processing

- Service with microwave-plasma system (TEPLA)
- Removal of photoresists and polymers

Lithographic equipment

- Microwave-plasma processor TEPLA 300 SEMI AUTO
- Coating systems with and without Gyrset up to a substrate size of 5 inch
- Bake systems:
 - Programmable precision hotplates
 - Infrared baker
 - Convection ovens
- Exposure tool maskaligner SUSS MA 56 M
- Film thickness measurement - DEKTAK (profilometer) for films up to 300 µm
- FTP 500 (ellipsometer) for films up to 3 µm
- Nickel electroforming (Ni-sulfamate) of 4-inch wafers – film thickness up to 80 µm

— Product Overview —

Negative tone photoresists

| Resist | Thickness (3000 rpm) | Developer | Features |
|--|--|---|--|
| ma-N 405 ma-N 415 ma-N 420 ma-N 440 ma-N 490 | 0.5 µm 1.5 µm 2.0 µm 4.0 µm 7.5 µm | ma-D 331S ma-D 332S ma-D 332S ma-D 332S ma-D 332S | - for lift-off processes λ = 365 nm |
| ma-N 1405 ma-N 1407 ma-N 1410 ma-N 1420 | 0.5 µm 0.7 µm 1.0 µm 2.0 µm | ma-D 533S ma-D 533S ma-D 533S ma-D 533S | - for lift-off processes thermally stable up to 170 °C suitable for metal deposition by sputtering λ = 365/405 nm |
| ma-N 2401 ma-N 2403 ma-N 2405 ma-N 2410 | 0.10 µm 0.30 µm 0.50 µm 1.00 µm | ma-D 532 ma-D 532 ma-D 532 ma-D 532 | - DUV and <u>e-beam resists</u> high plasma etch stability |

→ other thicknesses on demand

Positive tone photoresists

| Resist | Thickness (3000 rpm) | Developer | Features |
|---|--|--|---|
| ma-P 1205 ma-P 1210 ma-P 1215 ma-P 1225 ma-P 1240 | 0.5 µm 1.0 µm 1.5 µm 2.5 µm 4.0 µm | ma-D 331 ma-D 331 ma-D 331 ma-D 331 ma-D 331 | - Well suitable as an etch mask exhibiting high dry and wet etch resistance λ = 365 nm/ 405 nm/ 436 nm high stability in acid and alkaline plating baths |
| ma-P 1275 ma-P 1275 ma-P 1275 | 7.5 µm 30 µm (350 rpm/90 s) 60 µm (double coating) | ma-D 331 ma-D 331 ma-D 331 | - <u>high viscosity photoresist</u> with high stability in acid and alkaline plating baths and in wet and dry etch processes specifically designed for electroplating of structures in 3D UV microforming |

→ other thicknesses on demand



Thermoplastic Polymers for Nanoimprint Lithography

| mr-I 7000 | Thickness (3000 rpm) | Resolution * | Features |
|-----------|----------------------|--------------|--|
| mr-I 7010 | 100 nm | ≤ 50 nm | <ul style="list-style-type: none"> - T_g 60 °C - Excellent film quality - Imprint temperatures 125 - 150 °C - Imprint pressure 50 bar - Plasma etch resistance superior to PMMA - Etch selectivity to SiO₂ ~ 2 (CHF₃ plasma) |
| mr-I 7020 | 200 nm | ≤ 50 nm | |
| mr-I 7030 | 300 nm | ≤ 50 nm | |

| mr-I 8000 | Thickness (3000 rpm) | Resolution * | Features |
|-----------|----------------------|--------------|---|
| mr-I 8010 | 100 nm | ≤ 50 nm | <ul style="list-style-type: none"> - T_g 115 °C - Excellent film quality - Imprint temperatures 170 - 190 °C - Imprint pressure 50 bar - Plasma etch resistance superior to PMMA - Etch selectivity to SiO₂ ~ 2 (CHF₃ plasma) |
| mr-I 8020 | 200 nm | ≤ 50 nm | |
| mr-I 8030 | 300 nm | ≤ 50 nm | |

| mr-I PMMA (35k – 120k) | Thickness (3000 rpm) | Resolution * | Features |
|-------------------------------------|----------------------|--------------|---|
| mr-I PMMA 35 k ¹⁾ 100 nm | 100 nm | ≤ 50 nm | <ul style="list-style-type: none"> - T_g 105 °C - Excellent film quality - Imprint temperatures 150 - 180 °C - Imprint pressure 50 bar - Low molecular weights (35k, 75k, 120k) - Suited for fundamental investigations <p>¹⁾ or 75 k or 120 k</p> |
| mr-I PMMA 35 k ¹⁾ 200 nm | 200 nm | ≤ 50 nm | |
| mr-I PMMA 35 k ¹⁾ 300 nm | 300 nm | ≤ 50 nm | |
| mr-I PMMA 35 k ¹⁾ 400 nm | 400 nm | ≤ 50 nm | |
| mr-I PMMA 35 k ¹⁾ 500 nm | 500 nm | ≤ 50 nm | |

* Depending on stamp resolution



Thermoplastic Polymers for Nanoimprint Lithography with Improved Behaviour

| mr-I 7000E | Thickness (3000 rpm) | Resolution * | Features |
|------------|----------------------|--------------|--|
| mr-I 7010E | 100 nm | ≤ 50 nm | - Tg 60 °C - Excellent film quality - Imprint temperatures 125 - 150 °C - Imprint pressure 20 - 50 bar - Plasma etch resistance superior to PMMA - Etch selectivity to SiO ₂ about 2 (CHF ₃ plasma) |
| mr-I 7020E | 200 nm | ≤ 50 nm | |
| mr-I 7030E | 300 nm | ≤ 50 nm | |

| mr-I 8000E | Thickness (3000 rpm) | Resolution * | Features |
|------------|----------------------|--------------|---|
| mr-I 8010E | 100 nm | ≤ 50 nm | - Tg 115 °C - Excellent film quality - Imprint temperatures 170 - 190 °C - Imprint pressure 20 - 50 bar - Plasma etch resistance superior to PMMA - Etch selectivity to SiO ₂ about 2 (CHF ₃ plasma) |
| mr-I 8020E | 200 nm | ≤ 50 nm | |
| mr-I 8030E | 300 nm | ≤ 50 nm | |

* Depending on stamp resolution

Imprint characteristics superior to mr-I 7000 and mr-I 8000

- Lower imprint pressure
- Lower residual layer thickness
- Shorter cycle times due to faster imprint



New Curing Polymer for Nanoimprint Lithography

| mr-I 9000E | Thickness (3000rpm) | Resolution * | Features |
|------------|---------------------|--------------|---|
| mr-I 9010E | 100 nm | 50 nm | <ul style="list-style-type: none"> - T_g 35 °C before curing - Excellent film quality - Nearly isothermal imprint process: <ul style="list-style-type: none"> • imprint temperature 120 °C • mould release at 100 °C - Curing and increase in T_g to $T_{g,cured}$ during imprint - Imprint pressure 50 bar - Very low residual layer thickness down to 5 nm - Plasma etch resistance comparable to conventional novolak-based photoresists - Attainable smallest feature size at least 50 nm (depending on stamp resolution) |
| mr-I 9020E | 200 nm | 50 nm | |
| mr-I 9030E | 300 nm | 50 nm | |

* Depending on stamp resolution

Photochemically Curing Polymers for Thermal Nanoimprint Lithography

| mr-NIL 6000 | Thickness (3000rpm) | Resolution * | Features |
|---------------|---------------------|--------------|---|
| mr-NIL 6000.1 | 100 nm | 50 nm | <ul style="list-style-type: none"> - T_g 40 °C before curing - photochemically curing - Excellent film quality - Imprinting, curing by UV flood exposure and post exposure bake (PEB) during imprinting and mould release at the same temperature - Very low residual layer thickness < 10 nm - Excellent pattern transfer fidelity - High plasma etch resistance comparable - Attainable smallest feature size at least 50 nm (depending on stamp resolution) |
| mr-NIL 6000.2 | 200 nm | 50 nm | |
| mr-NIL 6000.3 | 300 nm | 50 nm | |

* Depending on technology

ORMOCER®s – inorganic-organic hybrid polymers

| Polymer | Thickness ¹ (3000 rpm) (1000 - 5000 rpm) | Refractive index @ 635 nm | Developer Thinner | Features |
|----------|---|------------------------------|----------------------|---|
| Ormocore | 22 µm 10 µm - 75 µm | 1.553 | Ormodev Ormothin | - Core material for polymer optical waveguides |
| Ormoclad | 19 µm 10 µm - 89 µm | 1.538 | Ormodev Ormothin | - Cladding material in planar polymer, optical wave guiding |
| Ormocomp | 32 µm 15 µm - 150 µm | 1.520 ² | Ormodev Ormothin | - UV curable polymer for applications in microoptics, e.g. lenses, lens arrays, prisms, optical couplers and connectors |

¹ Depending on coating equipment, ² @ 588 nm

Unique Features

- Solvent-free UV curable viscous liquids
- Thermal stability after curing up to 270 °C
- i-line, broadband exposure
- Patterning by UV lithography, replication technologies and/or rapid prototyping
- Compatible to conventional lithography equipment
- Suitable for datacom and telecom applications

Due to their optical properties ORMOCER®s are excellently suited for new developments in integrated optics, electronics, optoelectronics.

EpoCore and EpoClad – New Materials for Optical Wave Guides in PCB

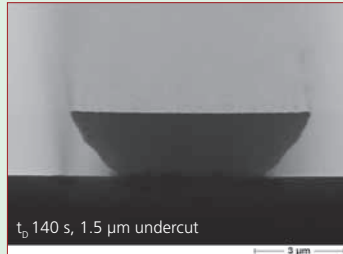
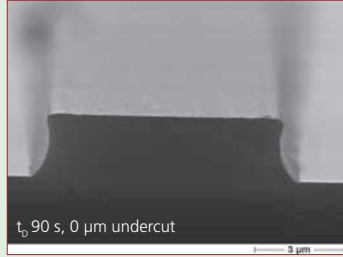
| Polymer | Thickness ¹ (1500 rpm) (1000 - 5000 rpm) | Refractive index @ 830 nm | Developer Thinner | Features |
|---------|---|------------------------------|----------------------|---|
| EpoCore | 50 µm 10 µm - 60 µm | 1.58 | Ormodev 600 | - Core material for planar polymer optical waveguides |
| EpoClad | 70 µm 10 µm - 100 µm | 1.57 | Ormodev 600 | - Cladding material in planar polymer, optical wave guiding |

¹ Depending on coating equipment, ² @ 588 nm

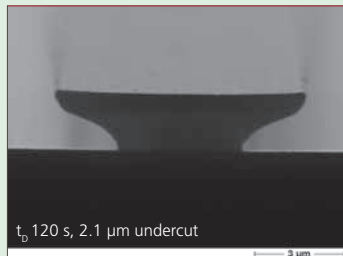
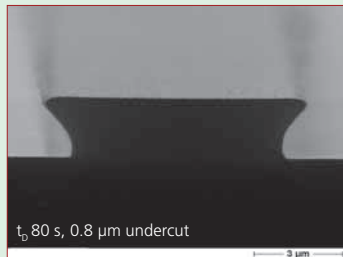
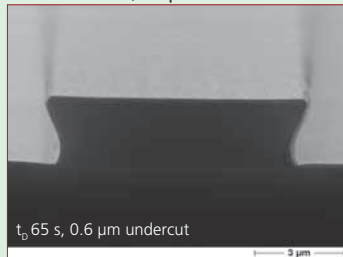
ma-N 400 and ma-N 1400 - Negative Tone Photoresists

Conventional Pattern Transfer and Single - Layer Lift - Off

ma-N 400, 2 µm thick



ma-N 1400, 2 µm thick



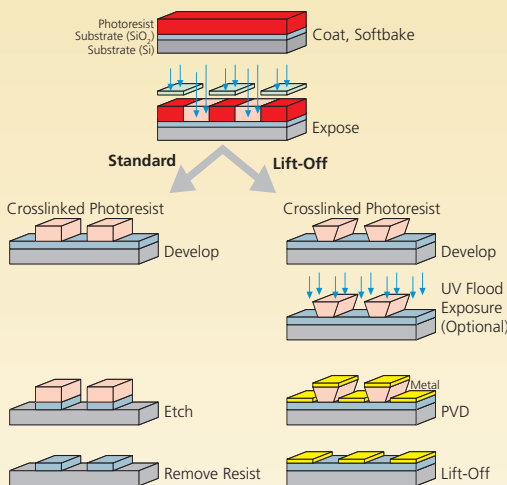
Unique features

- High wet and dry etch resistance
- Good thermal stability of the resist pattern
- Tunable pattern profil: vertical to undercut
- Aqueous alkaline development
- Easy to remove
- Based on safe solvents
- Resists available in a variety of viscosities

Applications

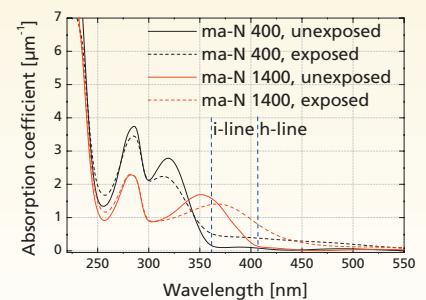
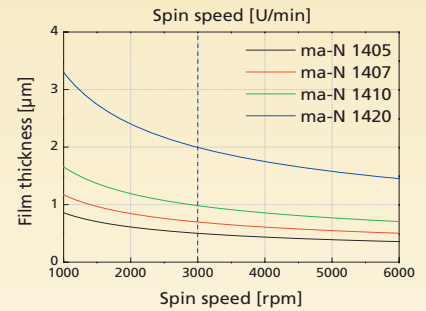
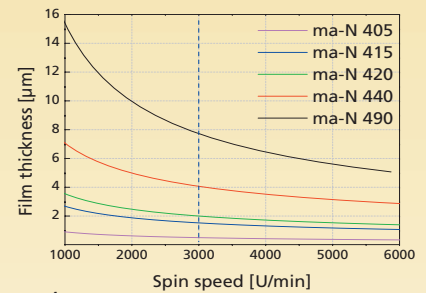
- Microelectronics and micro systems technology
- Mask for lift-off processes
- Etch mask for semiconductors and metals
- Well suitable for implantation

Standard and Lift-off process flow



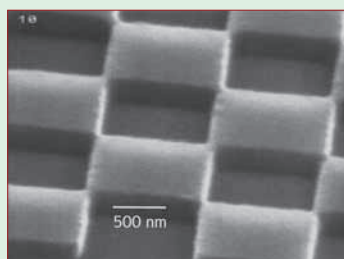
Technical data

| Resist | ma-N 400 | µm | ma-N 1400 | µm |
|----------------------|--|----------------|---|-----|
| Film thickness | ma-N 405 | 0.5 | ma-N 1405 | 0.5 |
| | ma-N 415 | 1.5 | ma-N 1407 | 0.7 |
| | ma-N 420 | 2.0 | ma-N 1410 | 1.0 |
| | ma-N 440 | 4.1 | ma-N 1420 | 2.0 |
| | ma-N 490 | 7.5 | | |
| | Spin coating / time | 3000 rpm, 30 s | | |
| Spectral sensitivity | 300 - 380 nm | | 300 - 410 nm | |
| Thermal stability | up to 110 °C, for metal evaporation | | up to 160 °C, for metal evaporation and sputtering | |

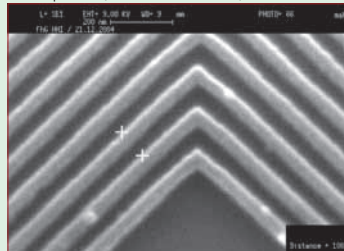


ma-N 2400 — Negative Tone Photoresist Series

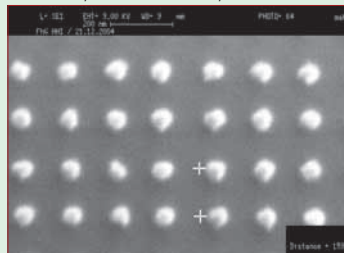
E-Beam and Deep UV Sensitive



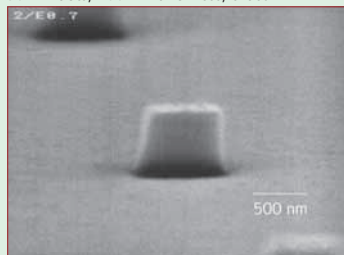
Chess pattern, 300 nm thickness, e-beam



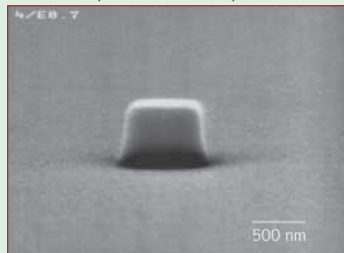
50 nm L&S, 100 nm thickness, e-beam



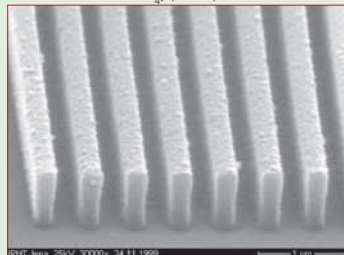
50 nm dots, 100 nm thickness, e-beam



800 nm dots, 750 nm thickness, e-beam



Dot after RIE with CF₄ (60 W)



250 nm L&S, 800 nm thickness

(Courtesy of FHG - HHI / IPHT Jena)

1.06.03.28.03

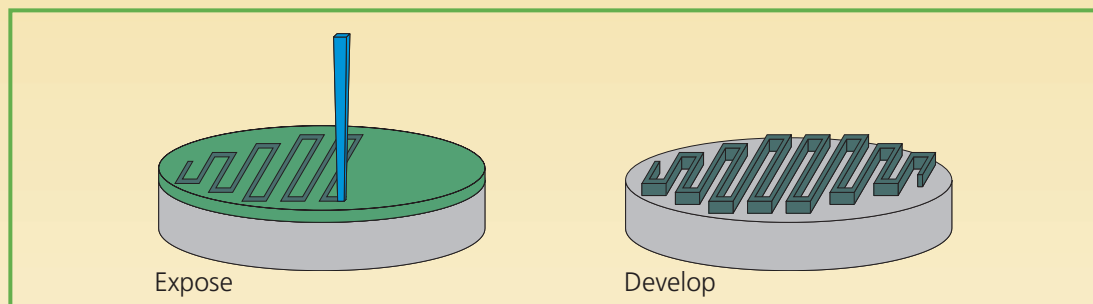
Unique features

- High wet and dry etch resistance
- Good thermal stability
- Excellent pattern resolution - down to 30 nm
- Aqueous alkaline development
- Easy to remove
- Resists available in a variety of viscosities

Applications

- Manufacturing of semiconductor devices
- Use in micro- and nanoelectronics
- Mask for etching, e.g. Si, SiO₂, Si₃N₄ or metals
- Mask for ion implantation
- Stamp fabrication for NIL

ma-N 2400 is well suited for e-beam exposure

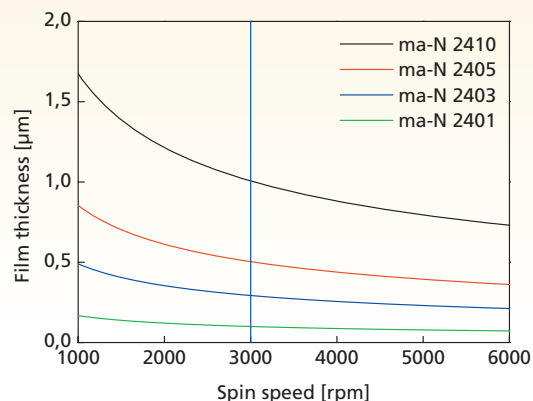
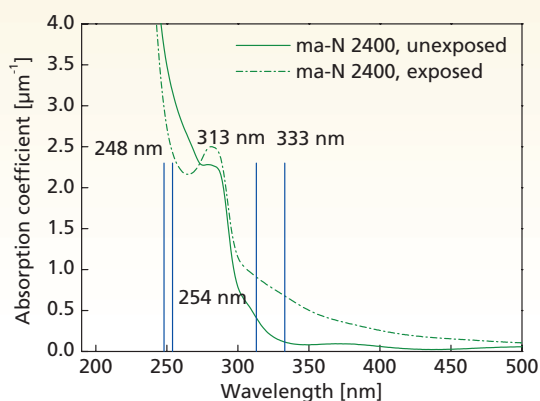


Technical data

| Resist | | ma-N 2401 | ma-N 2403 | ma-N 2405 | ma-N 2410 |
|--|---------------------|-----------|-----------|-----------|-----------|
| Film thickness | nm | 100 | 300 | 500 | 1000 |
| Spin coating | rpm/ s | 3000/ 30 | | | |
| Exposure dose - E-beam 20 keV ¹ | μC cm ⁻² | 120 - 200 | 170 - 235 | 170 - 250 | - |
| Exposure dose - E-beam 50 keV ¹ | μC cm ⁻² | 220 - 350 | 250 - 350 | 300 - 350 | - |
| Exposure dose - Deep UV ² | mJ cm ⁻² | - | 260 | 330 | 420 |
| Pattern resolution | E-beam | nm | 50 | 100 | 150 |
| | Deep UV | nm | < 50 | 200 | 300 |

¹ exposure dose depends on the pattern size/ resolution

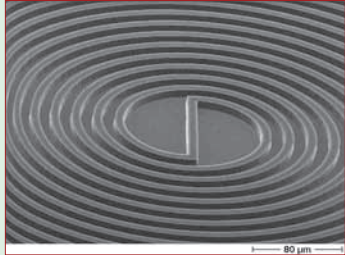
² broadband exposure, intensity measured at 260nm



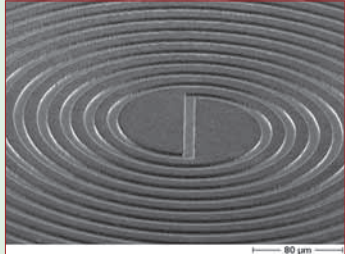
ma-P 1275 - Positive Tone Photoresist

Ultra Thick Resist for UV Lithography

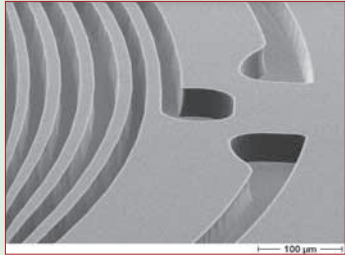
Resist patterning with mask aligner, broadband exposure



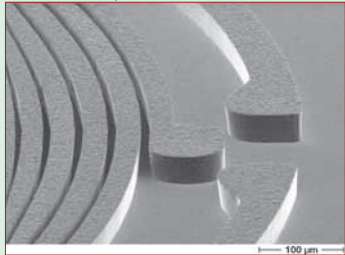
ma-P 1275, 7.5 µm thickness



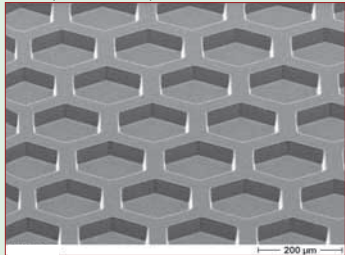
Electroplated Ni, 5 µm thickness



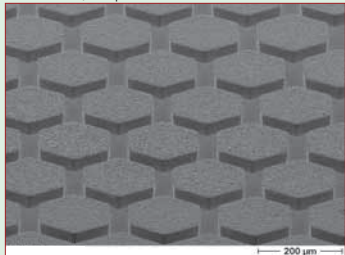
ma-P 1275, 30 µm thickness



Electroplated Ni, 28 µm thickness



ma-P 1275, 40 µm thickness



Electroplated Ni, 38 µm thickness

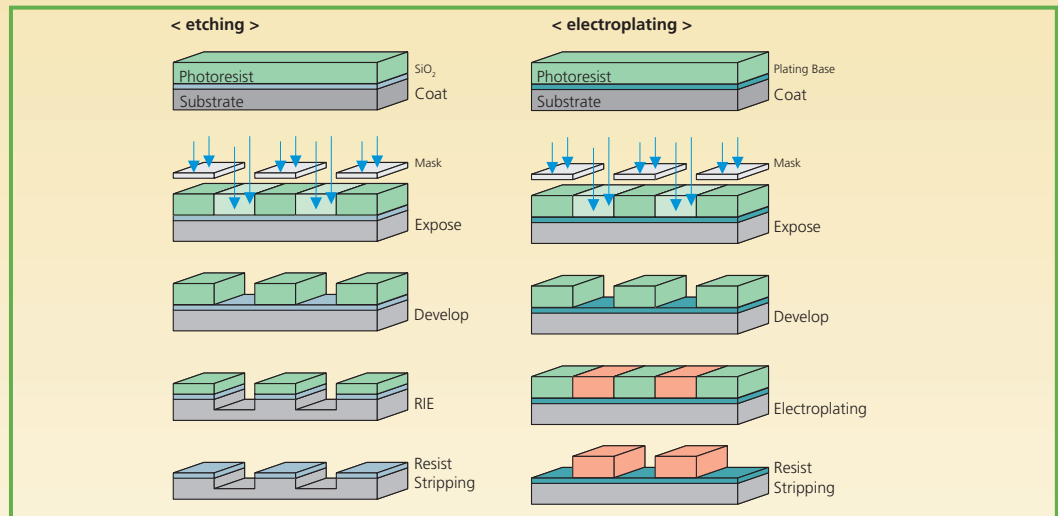
Unique features

- Outstanding pattern stability in wet etch processes and acid and alkaline plating baths from pH 1 - 13.5
- Highly stable in dry etch processes e.g. CHF_3 , CF_4 , SF_6
- Aqueous alkaline development
- Easy to remove
- Side wall angle up to 84°

Applications

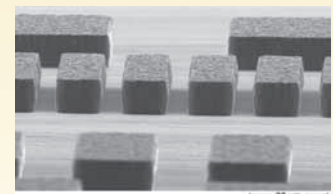
- Moulds for electroplating, e.g.
 - Micro optical components
 - Micro springs
 - Bumping
- Mask for etching e.g.
 - Si, SiO_2
 - Metals
 - Semiconductors
- Mask for ion implantation

Process flow for

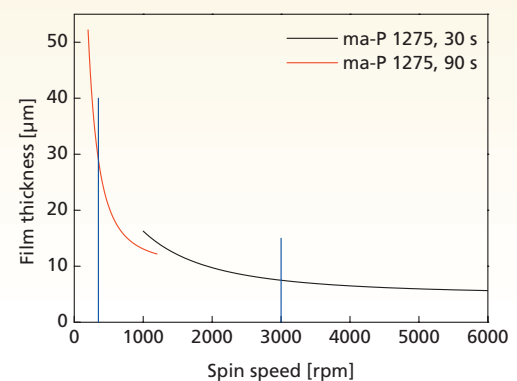
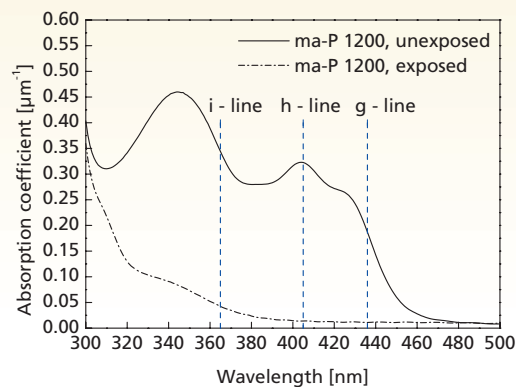


Technical data

| | | | | | |
|----------------|-----|-------|-------|-------|-------|
| Film thickness | µm | 7.5 | 20 | 30 | 40 |
| Spin coating | rpm | 3000 | 500 | 350 | 250 |
| Spin time | s | 30 | 90 | 90 | 90 |
| Aspect ratio | | 3 - 4 | 3 - 4 | 3 - 4 | 3 - 4 |



Cuboid Ni structures, 17 µm thickness



Thermoplastic Polymers for Nanoimprint Lithography

mr-I 7000, mr-I 8000 and mr-I PMMA - Special Polymers for NIL

Unique features and Applications

- Excellent film quality
- Plasma etch resistance superior to PMMA
- Application as etch mask (single layer process)
- Attainable smallest feature size at least 50 nm (depending on stamp resolution)
- Safe solvents

mr-I 7000

- T_g 60 °C
- Etch selectivity to SiO_2 about 2 (CHF_3 plasma)
- Imprint temperatures 110 - 140 °C
- Standard ready-to-use solutions

| Type | Film thickness |
|-----------|----------------|
| mr-I 7010 | 100 nm |
| mr-I 7020 | 200 nm |
| mr-I 7030 | 300 nm |

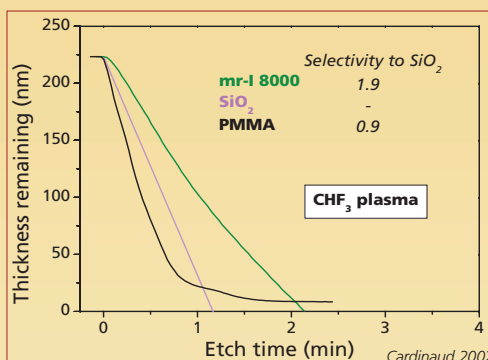
mr-I 8000

- T_g 115 °C
- Etch selectivity to SiO_2 about 2 (CHF_3 plasma)
- Imprint temperatures 160 - 190 °C
- Standard ready-to-use solutions

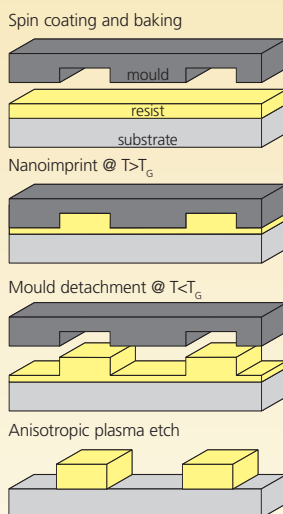
| Type | Film thickness |
|-----------|----------------|
| mr-I 8010 | 100 nm |
| mr-I 8020 | 200 nm |
| mr-I 8030 | 300 nm |

mr-I PMMA

- T_g 105 °C
- Suited for fundamental investigations
- Imprint temperatures 150 - 180 °C
- Standard ready-to-use solutions
- Different molecular weights (35 k, 75 k, 120 k)

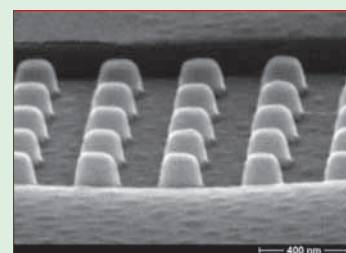


NIL process scheme

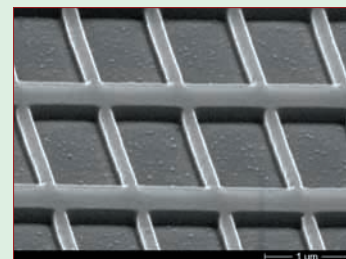


| Type | Film thickness |
|------------------------------------|----------------|
| mr-I PMMA 35k ¹⁾ 100 nm | 100 nm |
| mr-I PMMA 35k ¹⁾ 200 nm | 200 nm |
| mr-I PMMA 35k ¹⁾ 300 nm | 300 nm |
| mr-I PMMA 35k ¹⁾ 400 nm | 400 nm |
| mr-I PMMA 35k ¹⁾ 500 nm | 500 nm |

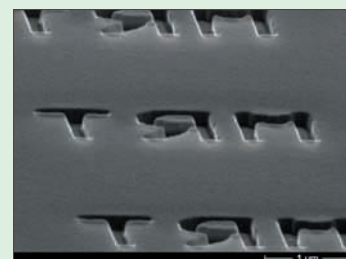
¹⁾ or 75k or 120k



200 nm dots in mr-I 8000



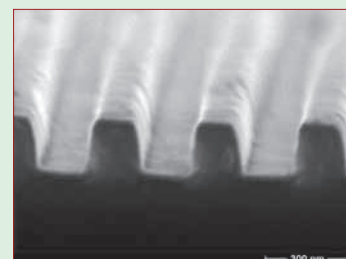
Imprinted structures in 300 nm thick mr-I 8000, minimum width: 200 nm



Initials of *micro resist technology* in mr-I 8000



Test structure in mr-I 7000, 200 nm lines

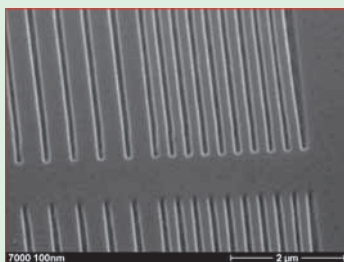


100 nm trenches in mr-I 7000

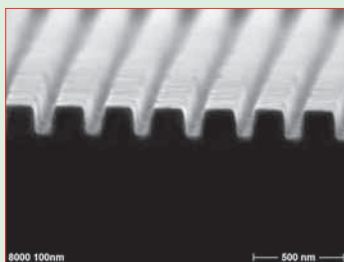
New Products by

Thermoplastic Polymers for Nanoimprint Lithography

mr-I 7000E, mr-I 8000E Thermoplastics with Improved Imprinting Behaviour



100 nm trenches, pitch 300 and 500 nm,
 Film thickness: 200 nm
 Imprint: 130 °C, 3 min, 50 bar
 Complete filling of stamp cavities
 Residual layer thickness < 10 nm



100 nm trenches, pitch 300 nm,
 Film thickness: 200 nm
 Imprint: 190 °C, 3 min, 50 bar
 Complete filling of stamp cavities
 Residual layer thickness < 10 nm

Unique features

- Excellent film quality
- Plasma etch resistance superior to PMMA
- Attainable smallest feature size at least 50 nm (depending on stamp resolution)
- Safe solvents

Imprint conditions

mr-I 7000E

- T_g 60 °C
- Imprint temperatures 125 - 150 °C
- Imprint pressure 20 - 50 bar
- Etch selectivity to SiO_2 about 2 (CHF_3 plasma)
- Ready-to-use solutions for 100 nm, 200 nm, 300 nm film thickness (3000 rpm)

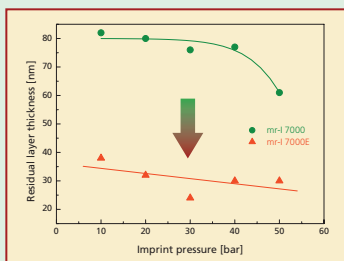
Imprint characteristics superior to mr-I 7000 and mr-I 8000 polymers

- ✓ Lower imprint pressure
- ✓ Lower residual layer thickness
- ✓ Shorter cycle times due to faster imprint

mr-I 8000E

- T_g 115 °C
- Imprint temperatures 170 - 190 °C
- Imprint pressure 20 - 50 bar
- Etch selectivity to SiO_2 about 2 (CHF_3 plasma)
- Ready-to-use solutions for 100 nm, 200 nm, 300 nm film thickness (3000 rpm)

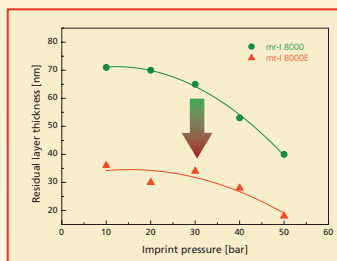
Lower residual layer thickness under gentle imprint conditions



mr-I 7000 vs. mr-I 7000E

Residual layer thickness as a function of imprint pressure

Film thickness: 200 nm
 Imprint: 10 s @ 100 °C
 Incomplete filling of stamp cavities

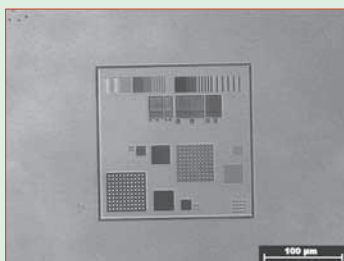


mr-I 8000 vs. mr-I 8000E

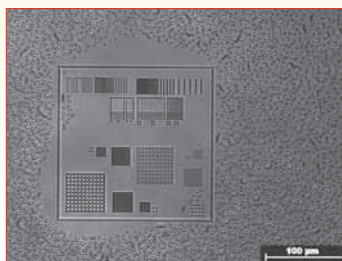
Residual layer thickness as a function of imprint pressure

Film thickness: 200 nm
 Imprint: 10 s @ 160 °C
 Incomplete filling of stamp cavities

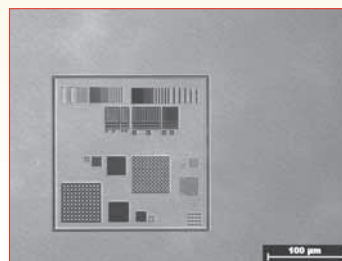
Defect-free imprints at lower pressure



mr-I 7000
 130 °C, 3 min,
50 bar
 no defects



mr-I 7000
 130 °C, 3 min,
20 bar
 insufficient polymer flow



mr-I 7000E
 130 °C, 3 min,
20 bar
 no defects

Curing Polymers for Thermal Nanoimprint Lithography

mr-I 9000 and mr-L 6000.5 for NIL

Unique features

- Excellent film quality
- Plasma etch resistance superior to PMMA
- Outstanding thermal stability
- Safe solvents

Applications

- Etch mask (single layer process)
- Low cost stamp fabrication
- Permanent applications

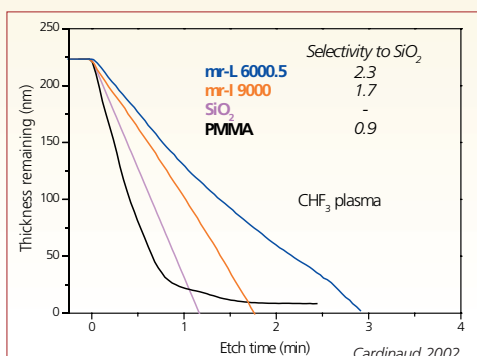
mr-I 9000

- T_g 65 °C
- **Thermal curing during imprint**
- Attainable smallest pattern size at least 50 nm (depending on stamp resolution)
- Etch selectivity to SiO₂ about 2 (CHF₃ plasma)
- Imprint temperatures 120 - 160 °C
- Standard ready-to-use solutions

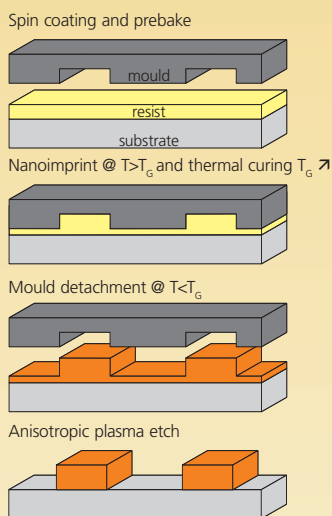
| Type | Film thickness |
|-----------|----------------|
| mr-I 9010 | 100 nm |
| mr-I 9020 | 200 nm |
| mr-I 9030 | 300 nm |

mr-L 6000.5

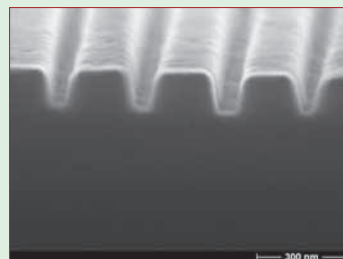
- T_g 35 °C
- **Curing after imprint by UV flood exposure and heat**
- Etch selectivity to SiO₂ > 2 (CHF₃ plasma)
- Attainable smallest pattern size at least 200 nm
- Imprint temperatures 80 - 120 °C
- Standard ready-to-use solution for 500 nm



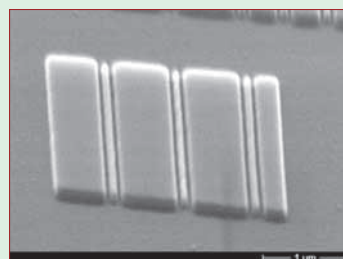
NIL process scheme for mr-I 9000



200 nm lines in mr-I 9000

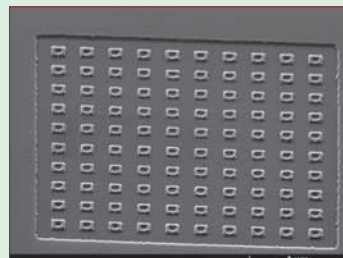
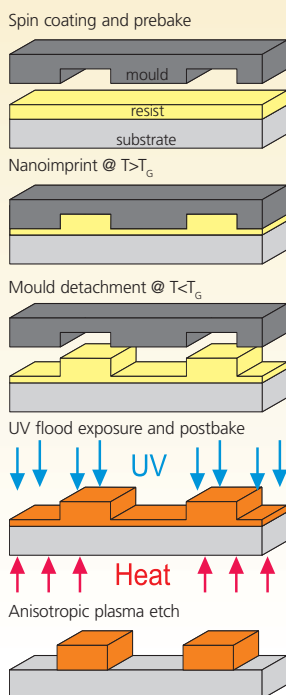


100 nm trenches in mr-I 9000

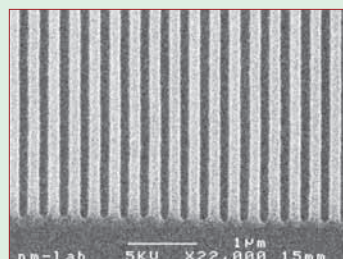


70 nm lines and 50 nm trenches in 300 nm thick mr-I 9000

NIL process scheme for mr-L 6000.5



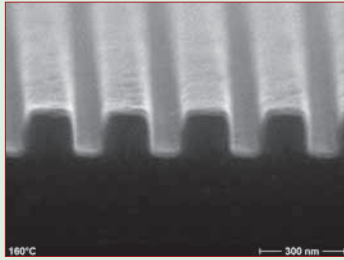
200 nm rings in mr-I 9000



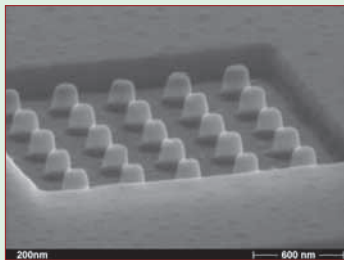
100 nm lines & spaces imprinted in 300 nm thick mr-L 6000XP (P. Carlberg 2002)

Curing Polymer for Thermal Nanoimprint Lithography

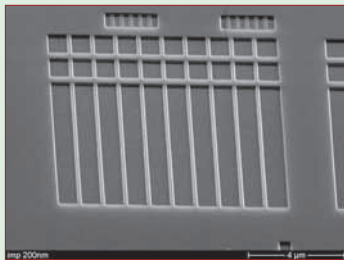
mr-I 9000E - Advanced thermoset for pattern transfer



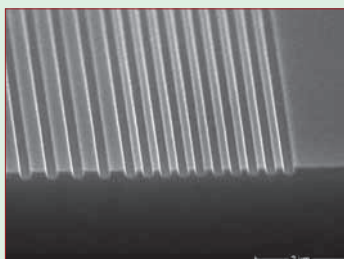
100 nm trenches, 300 nm pitch



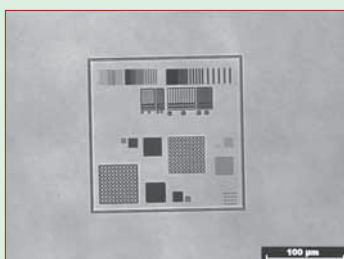
200 nm dots



200 nm lines



200 nm trenches

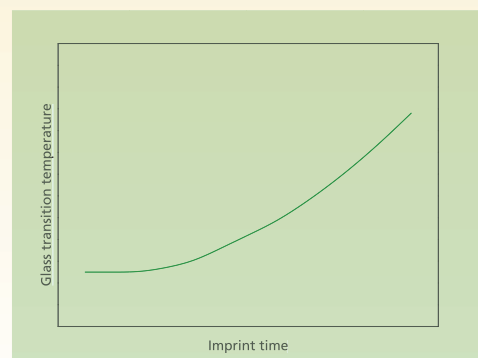


Uniform filling of patterns with different size (100 nm to 2 µm)

- Imprinting at moderate temperature and generating patterns with good thermal stability
- Applying nearly isothermal conditions

Unique features

- Excellent film quality
- T_g 35 °C before curing
- Nearly isothermal imprint process:
 - Imprint temperature 120 °C
 - Mould release at 100 °C
- **Curing** and increase in T_g to $T_{g,cured}$ **during imprint**
- Imprint pressure 50 bar
- Very low residual layer thickness down to 5 nm
- Excellent pattern transfer fidelity
- Plasma etch resistance comparable to conventional novolak-based photoresists
- Attainable smallest feature size at least 50 nm (depending on mould resolution)
- Ready-to-use solutions
- Safe solvents



Increase in T_g during imprinting

Applications

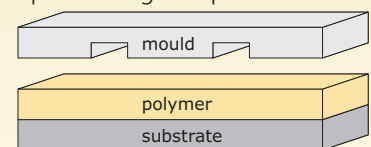
- Coating of various substrate materials, e.g. Si, SiO₂, Al
- Mask for **pattern transfer** processes
- Dry and wet etching
- Single and multilayer systems

| Type | Thickness ¹⁾ |
|------------|-------------------------|
| mr-I 9010E | 100 nm |
| mr-I 9020E | 200 nm |
| mr-I 9030E | 300 nm |

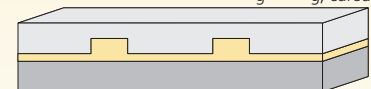
¹⁾ 3000 rpm, 30 s

NIL process - mr-I 9000E

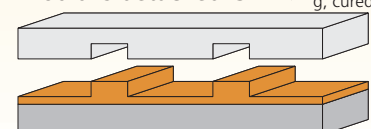
Spin coating and prebake



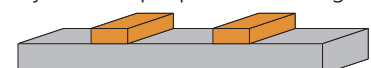
Nanoimprinting @ $T > T_g$ and thermal curing, $T_g \rightarrow T_{g,cured}$



Mould is detached @ $T < T_{g,cured}$

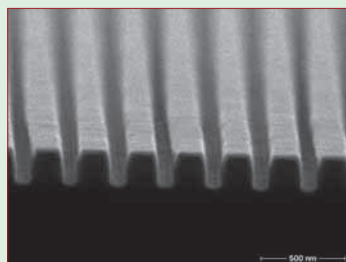


Residual polymer layer is removed by anisotropic plasma etching

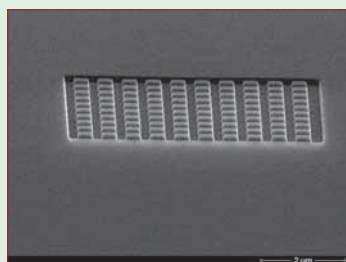


Photochemically Curing Resist for Thermal Nanoimprint Lithography

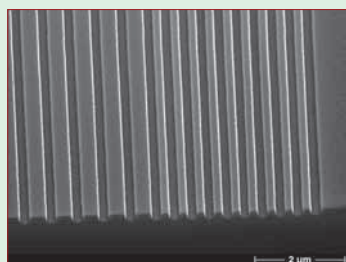
mr-NIL 6000 — High performance resist for pattern transfer and permanent applications



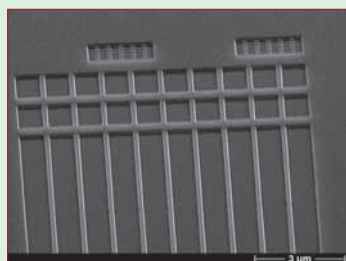
100 nm trenches, 300 nm pitch



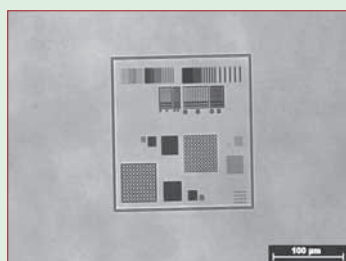
200 nm dots



200 nm trenches



200 nm lines



Uniform filling of patterns with different size (100 nm to 2 µm)

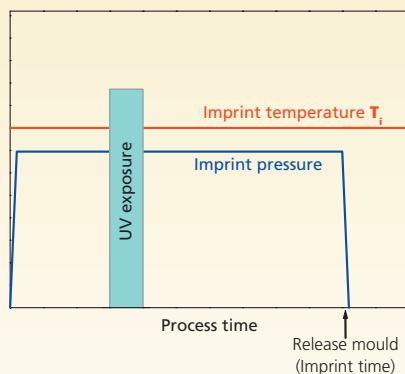
1.06.03.27.01

mr-NIL 6000 — tailored material for thermal nanoimprinting and photochemically curing as simultaneous process for the manufacturing of ultra fine structures

- Solid resist film after spin coating
- Imprinting at moderate temperature
- Isothermal imprint process

Unique features

- Excellent film quality
- T_g 40 °C before curing
- Imprinting, curing by UV flood exposure and post exposure bake (PEB) during imprinting and mould release **at the same temperature**
- Very low residual layer thickness < 10 nm
- Excellent pattern transfer fidelity
- Plasma etch resistance comparable to conventional novolak-based photoresists
- Ready-to-use solutions
- Safe solvents



| Type | Thickness ¹⁾ |
|---------------|-------------------------|
| mr-NIL 6000.1 | 100 nm |
| mr-NIL 6000.2 | 200 nm |
| mr-NIL 6000.3 | 300 nm |

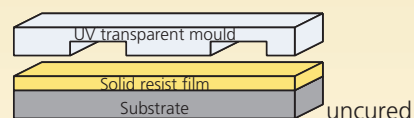
¹⁾ spin coating @ 3000 rpm, 30 s

Applications

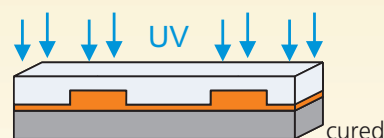
- Coating of various substrate materials, e.g. Si, SiO₂, Al
- Mask for **pattern transfer** processes
- Dry and wet etching
- Single and multilayer systems
- Permanent structures e.g. in microfluidics, optics

Process

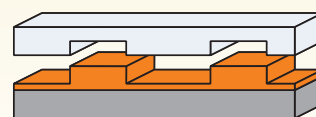
Spin coating and prebake



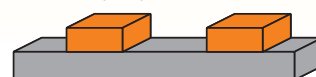
Nanoimprint @ $T_i > T_g$, UV flood exposure and post exposure bake



Mould detachment @ T_i

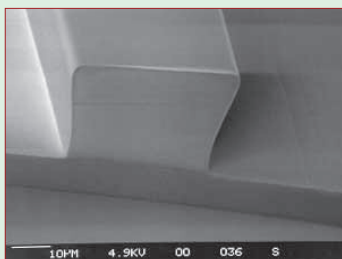


Anisotropic plasma etch

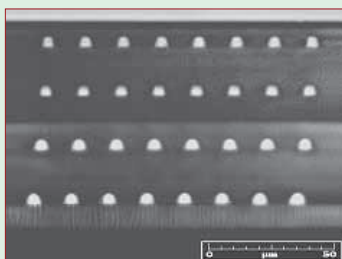


Ormocore and Ormoclad

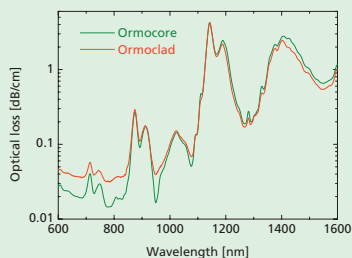
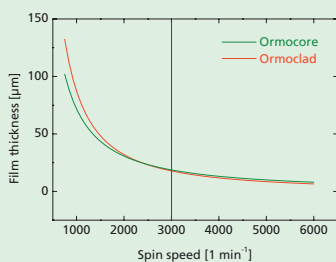
ORMOCER® System for Planar Optical Waveguides



Undercladding/ core of a multimode wave guide on silicon - ACREO/ Sweden



Multilayer optical fan out
 FHG - IOF/ Jena - Germany



Unique features

Photo patterning inorganic-organic hybrid polymers

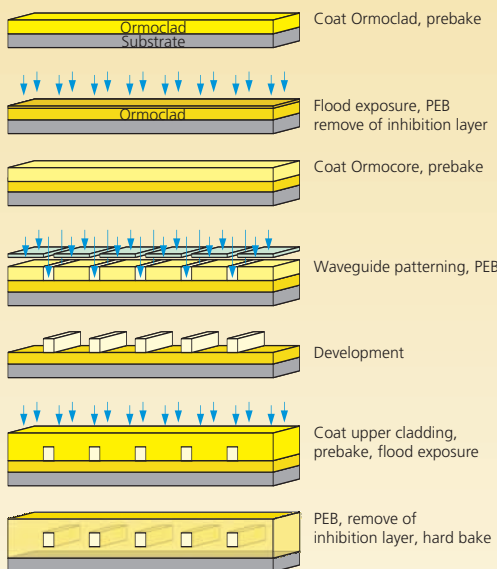
- UV patterning (lithography/ moulding)
- Exposure: i-line, broadband
- Tunable refractive index (core/ clad)
- Low optical loss at datacom wavelengths
- Thermally stable up to 270 °C
- 6 months shelf life

Applications

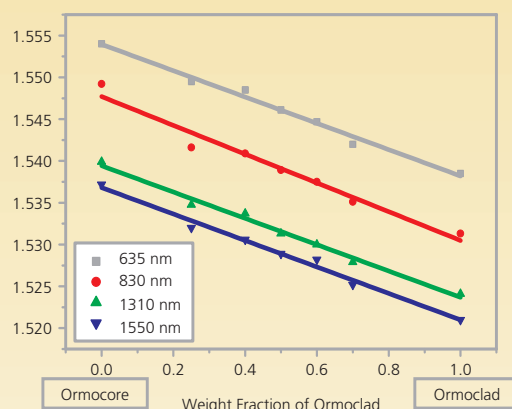
For manufacture of

- Multimode wave guides
- Singlemode wave guides
- Beam splitters
- Thermo-optical switches

Process flow for optical wave guides



Refractive index tuning



Optical loss (α)

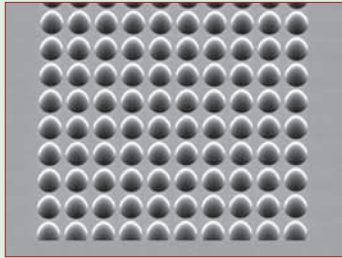
| Ormocore | Ormoclad |
|---|------------------------------------|
| < 0.1 dB cm ⁻¹ @ 633 nm | ≤ 0.1 dB cm ⁻¹ @ 633 nm |
| 0.23 dB cm ⁻¹ @ 1310 nm | 0.26 dB cm ⁻¹ @ 1310 nm |
| 0.5 - 0.6 dB cm ⁻¹ @ 1550 nm | 0.48 dB cm ⁻¹ @ 1550 nm |

Technical data

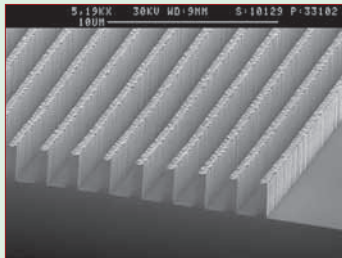
| Properties of the cured materials | Ormocore | Ormoclad |
|-----------------------------------|---|----------|
| Thermal stability | Weight loss < 5 % up to 270 °C (5 K min ⁻¹) | |
| Film quality | Good planarisation properties | |
| Thermal behaviour | duromeric | |
| Water absorption | < 0.5 % | |
| CTE (20 - 100 °C) | 100 - 130 ppm K ⁻¹ | |
| Rms roughness | 2 - 4 nm | |
| Shrinkage (during curing) | 2 - 5 Vol.-% | |
| Refractive index @ 635 nm | 1.553 | 1.534 |

Ormocomp — UV Curable Hybrid Polymer for Moulding

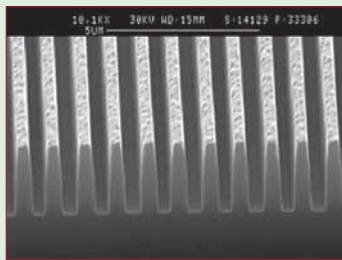
ORMOCER® for Microoptical Components Produced by UV moulding



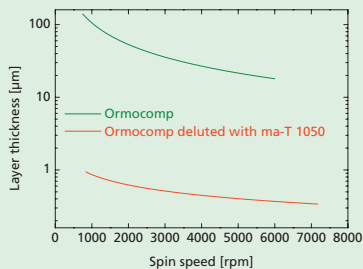
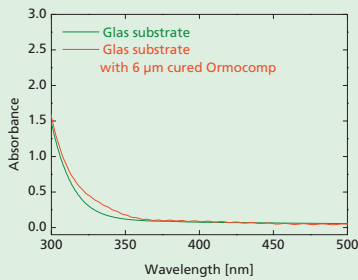
Replicated 10x10 micro lens array
 FHG -IOF Jena/ Germany



Optical grating
 FSU - Jena/ Germany



Optical grating
 FHG -IOF Jena/ Germany



Unique features

Ormocomp - UV curable material for imprinting

- UV patterning (lithography/ moulding)
- Exposure: i-line, broadband
- Fast curing
- Shrink during curing 5 - 7 Vol.%
- Thermally stable up to 270 °C
- 6 months shelf life
- Solvent free

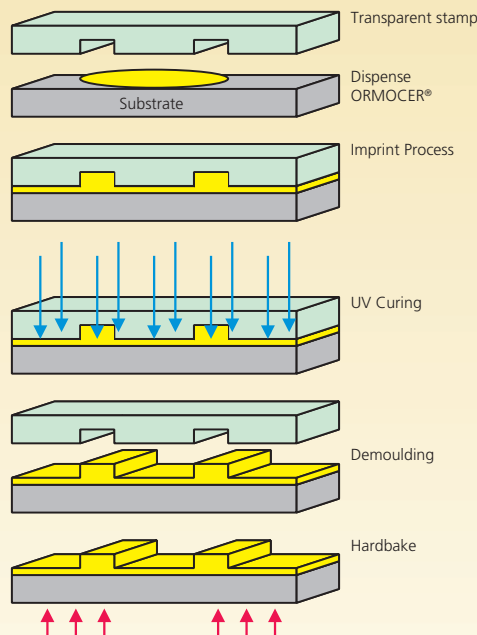
Applications

For manufacture of

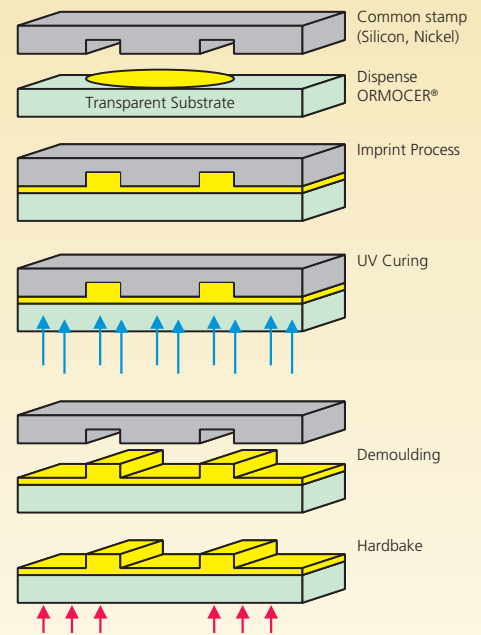
- Moulded gratings
- Micro lenses
- Micro lens arrays
- Optical couplers and connectors
- Prisms

Process flow UV moulding

< transparent stamp >



< common stamp >

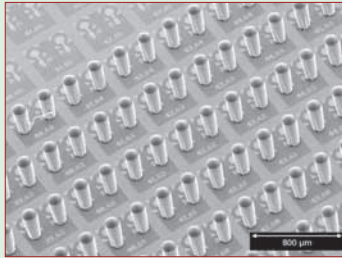


Technical data

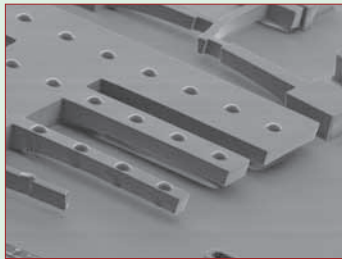
| Properties of the cured materials | Ormocomp |
|-----------------------------------|---|
| Thermal stability | Weight loss < 5 % up to 270 °C (5 K min ⁻¹) |
| Film quality | Good planarisation properties |
| Thermal behaviour | duromeric |
| Water absorption | < 0.5 % |
| CTE (20 - 100 °C) | 100 - 130 ppm K ⁻¹ |
| rms roughness | 2 - 4 nm |
| Shrinkage (during curing) | 5 - 7 Vol.-% |
| Refractive index @ 635 nm | 1.518 |

ORMOCER®s — Ormocore & Ormocomp for Microoptics

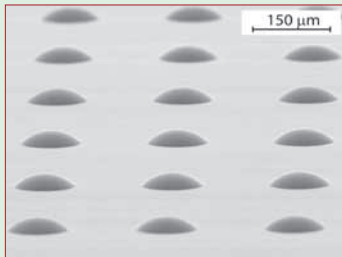
Materials and Technology for Innovative Microoptical Applications



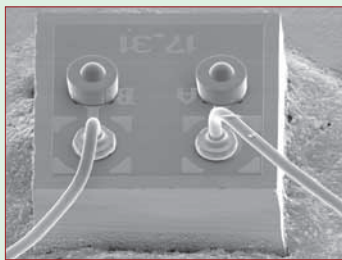
SEM of replicated sol-gel refractive microlenses on a VCSEL wafer substrate (Courtesy of Avalon)



Replicated ORMOCER® cantilever beams with microlenses. Length: 1mm, height: 50 µm, gap under the beams: 30µm (CSEM)



SEM of replicated microlenses in sol-gel material (CSEM)



Packaged replicated sol-gel lens on a VCSEL chip (CSEM/Avalon)

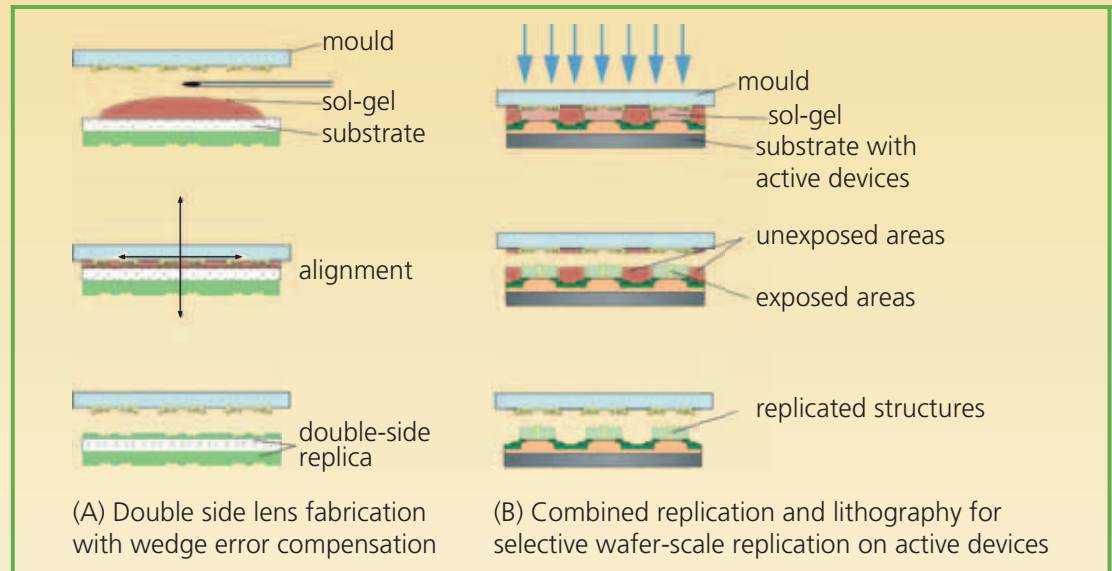
CSEM SA
 Badenerstrasse 569
 P.O. BOX
 CH-8048 Zuerich
 Telephon +41 1 497 1411
 Fax +41 1 497 1400
 www.csem.ch

Material

- UV patterning
- Thermally stable up to 270 °C
- Fast curing
- Solvent free

Technology

- Very high resolution to sub 200 nm linewidth
- Binary and continuous profile
- Positioning and mechanical alignment features in one mold
- Single elements or wafer scale



Physical properties

| Ormocore | Ormocomp |
|---|---------------------------------|
| n @ 635 nm: 1.553 | n @ 635 nm: 1.518 |
| n @ 800 nm: 1.543 | n @ 800 nm: 1.513 |
| Exposure dose: 300 - 1000 mJ cm ⁻² at 350 nm - UV 300 source recommended | |
| CTE: 100 - 130 ppm K ⁻¹ | |
| Shrinkage 3 - 5 % | Shrinkage 5 - 7 % |
| Highly transparent up to 400 nm and at datacom wavelengths | Highly transparent up to 400 nm |
| Thermal behavior: stable up to 270 °C | |

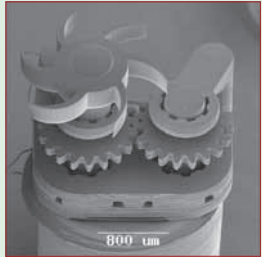
Applications

- Microoptical components and microsystems, optical sensors and measurement systems, telecom and datacom, displays and optical sensors and instruments

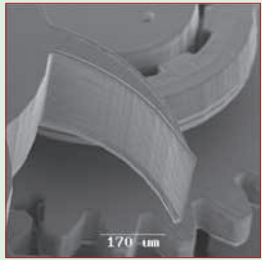
The μ -stereo Lithography Setup

Layer-by-Layer 3D micro patterning with ORMOCER®s

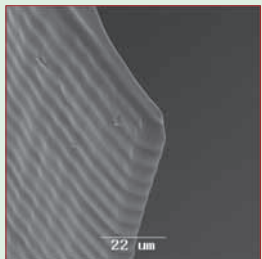
micro mechanical demonstrators, developed within the PRONTO project:



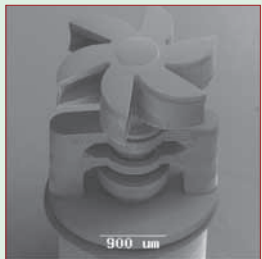
Windmill for fluidic media with a gearwheel connection



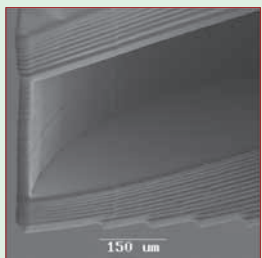
Detail view of a windmill sail



Detail view of the 10 μ m layers of a windmill sail



Windmill with cavities



Detail view of the windmill cavity

1.06.03.07.01

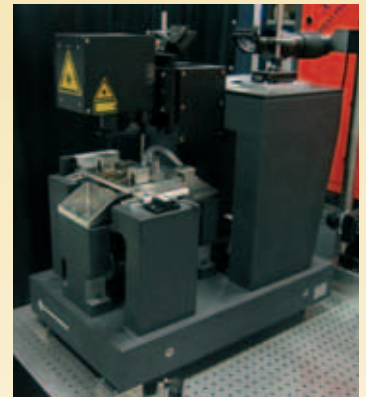
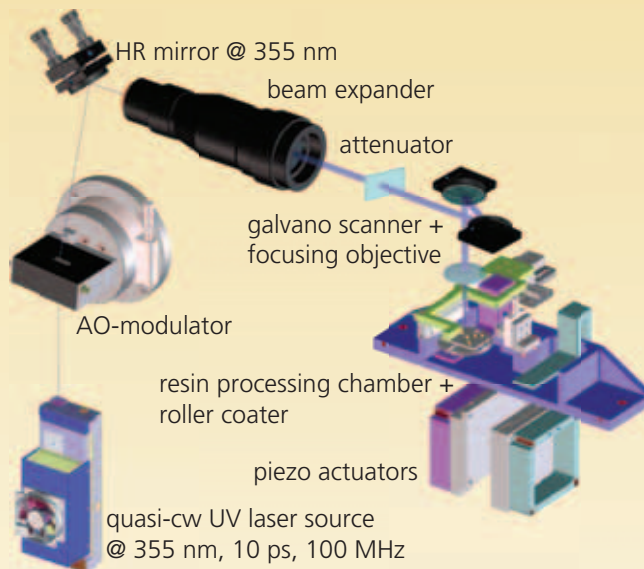
Unique features

- Laser: 355 nm, 20 mW, 100 MHz
- Scanner: 100 mm focal distance, scanning area 50 x 50 mm
- Resolution: < 10 μ m vertical 5 μ m lateral
- Positioning with piezo actuators

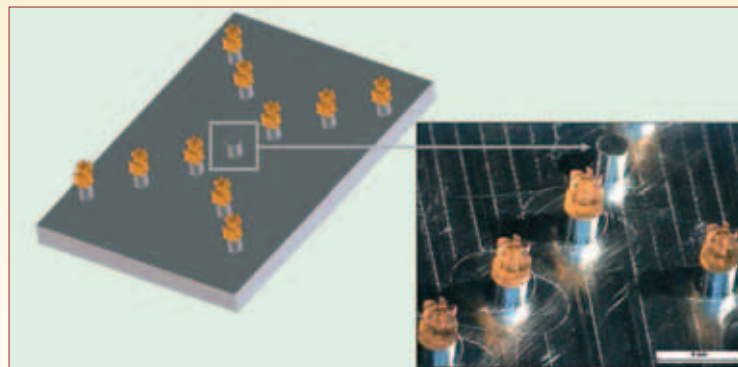
Applications

- Micro mechanical systems
- Micro sensors
- Micro fluidics
- Medicine and bio applications

Principle Setup



Photograph of the μ -stereo lithography setup



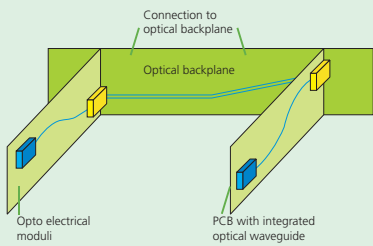
Substrate with 10 windmills built simultaneously



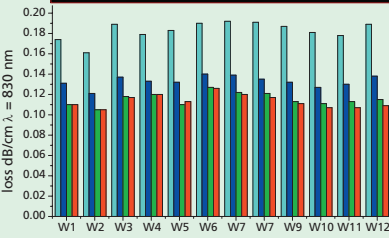
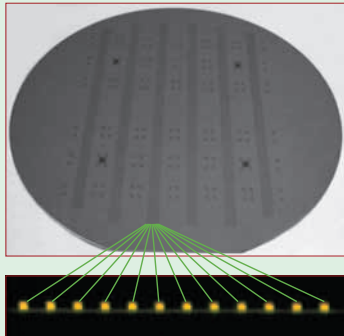
New Products by

EpoCore & EpoClad - New Materials for Optical Wave Guides in PCB

For New Generation Interconnection Technology (NegIT)

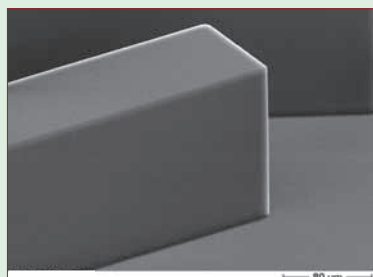


New Generation Interconnection Technology (NegIT)



after:
 Lamination 185 °C 23.5 kp/cm²
 Reflow 3 x 230 °C
 TCT 100 x -40/125 °C
 TCT 204 x -40/125 °C

Low optical loss @ $\lambda = 830$ nm
 after standard tests: 0.1 dB/cm

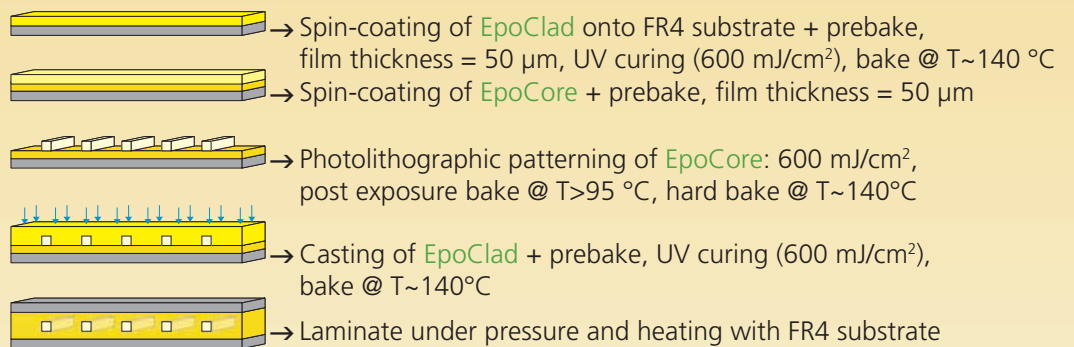


Unique features

- Standard Lithography and PCB technology processing
- UV patterning of core and cladding
- High transmittance @ 850 nm
- High heat and pressure resistance
- Tunable refractive index (core/cladding)

Applications

- Optical waveguides
- Etch mask
- Casting moulding
- Biosensors (multifunctional systems)
- UV resist



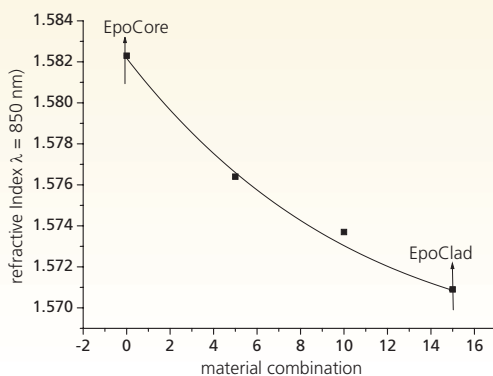
Technical data

| | |
|------------------------------|---|
| Resin type | Epoxy duromer |
| Waveguide | Refractive index @ $\lambda = 830$ nm: EpoCore 1.58, EpoClad 1.57 |
| Glass transition temperature | > 180 °C |
| Substrate | Standard FR4 (10x10 cm, 8 inch) |
| Lamination | Standard temperature > 185 °C, pressure 23 kp/cm ² |
| Standard tests | Reflow: 3 x 15 s @ T = 230 °C; TCT: 240 x -40 °C / +120 °C |
| Optical loss | ~0.2 dB/cm @ $\lambda = 850$ nm |

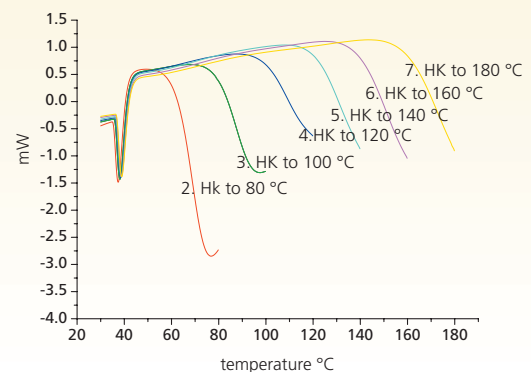
- Fabrication with conventional equipment (UV lithography and PCB)

- High thermal stability (> 230 °C), high glass transition temperature (> 180 °C)

- Excellent stability of embedded, laminated waveguides after reflow and TCT tests



Refractive index tuning by copolymerisation



EpoCore, DSC-curve after repeated measurements with different final temperatures

- We gratefully acknowledge all contributions of our partners. BMBF Förderkennzeichen NeGIT 16SV 1819

micro resist technology GmbH

Koepenicker Straße 325, Haus 211
12555 Berlin
Germany

Tel.: +49 30 65 76 21 92
Fax: +49 30 65 76 21 93
Email: mrt@microresist.de

www.microresist.de